

SuperQ™ 200V N-Channel Power MOSFET

FEATURES

- Industry leading $R_{DS(on)}$ in TOLL package
- High short-circuit withstand capability (SCWC)
- 100% UIS tested in production
- Low switching losses, Q_{sw} and E_{oss}
- Easier parallelling with $\pm 0.5V$ gate threshold

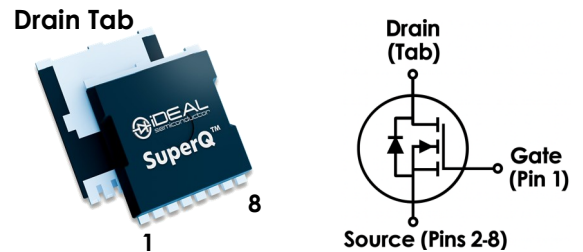
APPLICATIONS

- Motor control
- Boost converters and SMPS control FETs
- Secondary side synchronous rectifier

DESCRIPTION

Engineered for high-efficiency SMPS and motor drives, this 200V SuperQ MOSFET delivers ultra-low conduction and switching losses in a robust TOLL package. Featuring best-in-class $R_{DS(on)}$ and Q_{sw} , it minimizes heat dissipation at both full and partial loads.

PRODUCT SUMMARY



TOLL

Parameter	Value	Unit
$T_A = 25^\circ C$		
V_{DS}	200	V
$R_{DS(on),max}$	5.5	m Ω
I_D	151	A
Q_G	112	nC
Q_{sw}	8.3	nC
E_{oss}	4.0	μJ



ORDERING INFORMATION

Part Number	Package	Marking	Packaging
iS20M5R5S1T	TOLL	iS20M5R5S1	13" 2,000pcs T&R

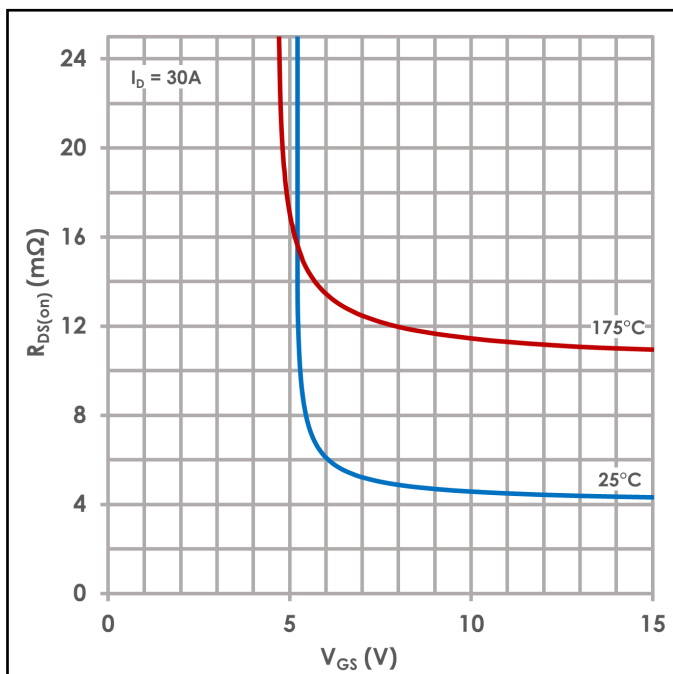


Figure 1: Typical Drain-Source On Resistance

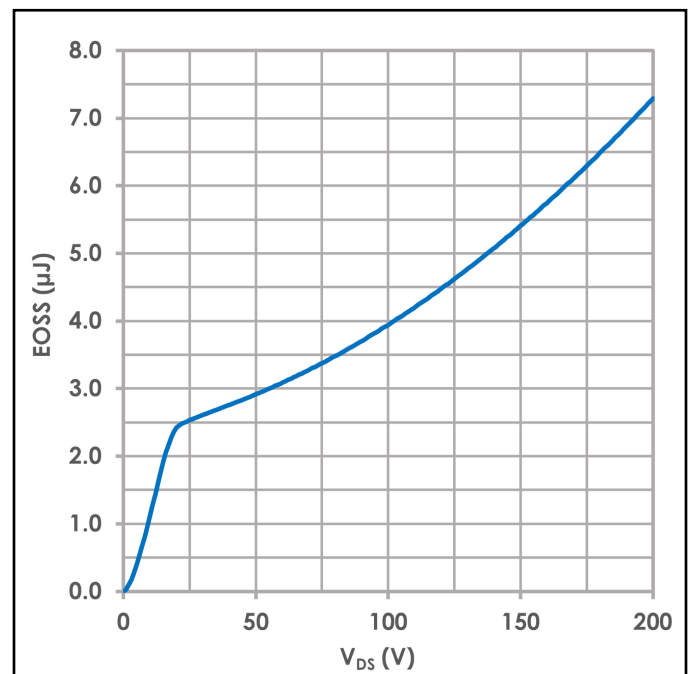


Figure 2: Typical C_{oss} Stored Energy

ABSOLUTE MAXIMUM RATINGS			
SYMBOL	PARAMETER (T _A = 25°C unless otherwise specified)	VALUE	UNIT
V _{GS}	Gate-to-source voltage	± 20	V
I _D	Continuous drain current (silicon limited), T _C = 25°C	151	A
	Continuous drain current (silicon limited), T _C = 100°C	107	
I _{DM}	Pulsed drain current	538	A
P _D	Power dissipation, T _C = 25°C	314	W
T _J , T _{stg}	Operating junction, storage temperature	-55 to 175	°C
E _{AS}	Avalanche energy, single pulse I _D = 94A, R _{GS} = 25Ω	443	mJ

THERMAL CHARACTERISTICS					
SYMBOL	PARAMETER (T _A = 25°C unless otherwise specified)	VALUE			UNIT
		MIN	TYP	MAX	
R _{θJC}	Junction-to-case thermal resistance - TOLL	-	-	0.5	°C/W
R _{θJA}	Junction-to-ambient thermal resistance ⁽¹⁾	-	-	50	°C/W

(1) 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.

ELECTRICAL CHARACTERISTICS (T _A = 25°C unless otherwise specified)						
SYMBOL	PARAMETER	TEST CONDITIONS	VALUE			UNIT
			MIN	TYP	MAX	
STATIC CHARACTERISTICS						
BV _{DSS}	Drain-to-source voltage	V _{GS} = 0V, I _D = 1mA	200	-	-	V
I _{DSS}	Drain-to-source leakage current	V _{GS} = 0V, V _{DS} = 160V, T _J = 25°C	-	0.1	1	μA
		V _{GS} = 0V, V _{DS} = 160V, T _J = 125°C ⁽²⁾	-	-	100	
I _{GSS}	Gate-to-source leakage current	V _{DS} = 0V, V _{GS} = 20V	-	1	100	nA
V _{GS(th)}	Gate-to-source threshold voltage	V _{DS} = V _{GS} , I _D = 300μA	3.1	3.5	4.1	V
R _{DS(on)}	Drain-to-source on-resistance	V _{GS} = 10V, I _D = 30A	-	4.6	5.5	mΩ
g _{fs}	Transconductance	V _{DS} = 10V, I _D = 30A	48	96	-	S
DYNAMIC CHARACTERISTICS						
C _{iss}	Input capacitance ⁽²⁾	V _{GS} = 0V, V _{DS} = 100V, f = 100kHz	-	8,366	10,876	pF
C _{rss}	Reverse transfer capacitance ⁽²⁾		-	37	48	
C _{oss}	Output capacitance ⁽²⁾		-	249	324	
C _{o(er)}	Effective output capacitance	V _{DS} = 0 to 100V, V _{GS} = 0V	-	396	-	
R _G	Series gate resistance	f = 1MHz	-	0.6	0.9	Ω
t _{d(on)}	Turn-on delay time	V _{DS} = 100V, V _{GS} = 10V, I _{DS} = 30A, R _{G,EXT} = 0 Ω	-	21.5	-	ns
t _r	Rise time		-	6.6	-	
t _{d(off)}	Turn-off delay time		-	46.7	-	
t _f	Fall time		-	5.1	-	
GATE CHARGE CHARACTERISTICS						
Q _G	Gate charge total ⁽²⁾	V _{DS} = 100V, I _D = 30A, V _{GS} = 0 to 10V	-	112	146	nC
Q _{sw}	Switching charge ⁽³⁾		-	8.3	-	
Q _{gd}	Gate to drain charge ^{(2) (3)}		-	4.0	5.2	
Q _{g(th)}	Gate charge at threshold ⁽³⁾		-	25.5	-	
Q _{gs2}	Gate to source charge ⁽³⁾		-	4.3	-	
V _{plateau}	Gate plateau voltage		-	5.5	-	V
Q _{oss}	Output charge ⁽²⁾	V _{DS} = 0 to 100V, V _{GS} = 0V	-	398	458	nC
E _{oss}	Capacitive stored energy		-	4.0	-	μJ
DIODE CHARACTERISTICS						
V _{SD}	Diode forward voltage	I _{SD} = 30A, V _{GS} = 0V	-	0.9	1.2	V
Q _{rr}	Reverse recovery charge	V _{DS} = 100V, I _F = 30A,	-	0.7	-	μC
t _{rr}	Reverse recovery time	di/dt = 100A/μs	-	151	-	ns

(2) Defined by design. Not subject to production test.

(3) Q_{sw} should be used for switching loss calculations. See Figure 16 for gate charge definitions. For more information see Q_{sw} application note on www.idealsemi.com

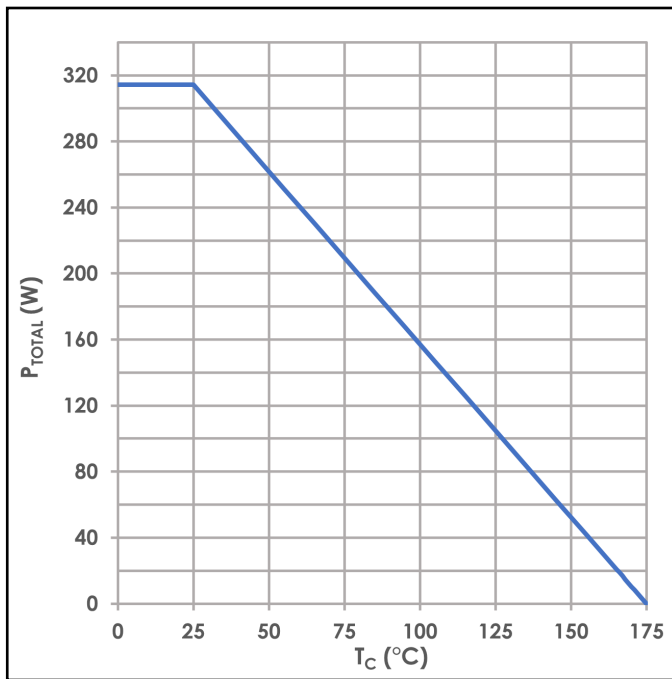


Figure 3: Power Dissipation

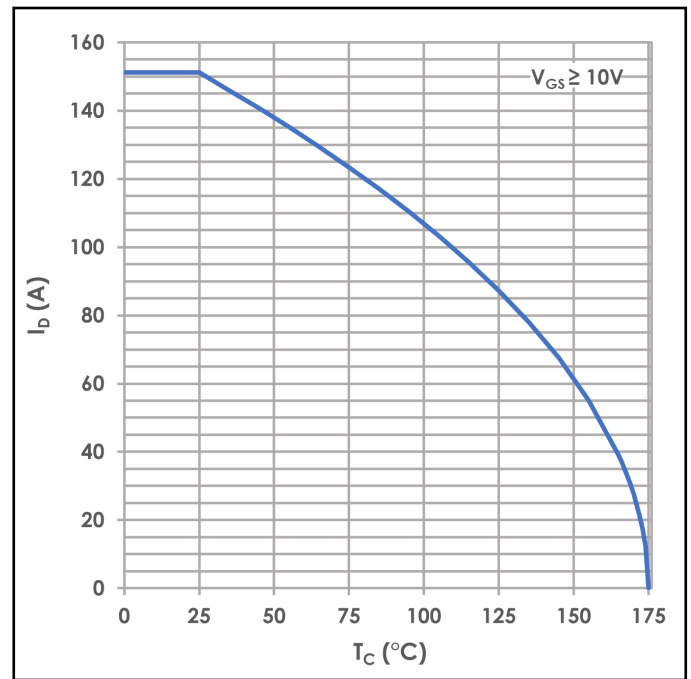


Figure 4: Drain Current

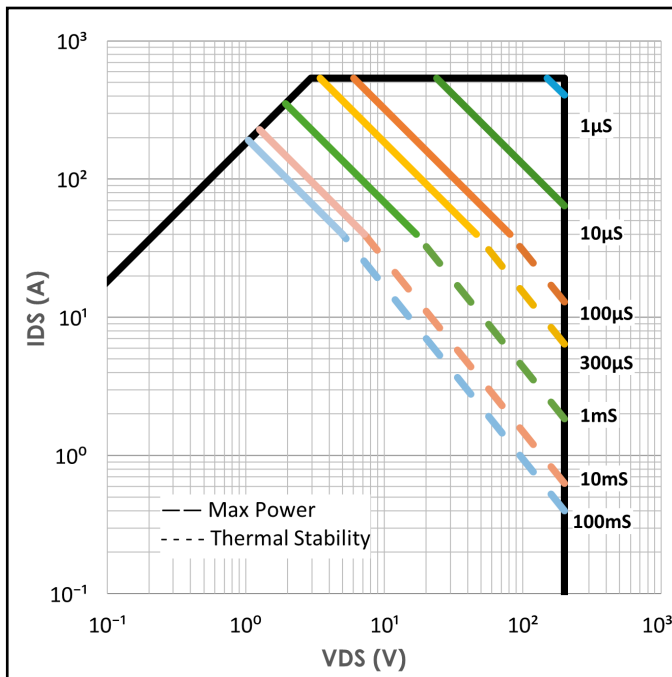


Figure 5: Safe Operating Area

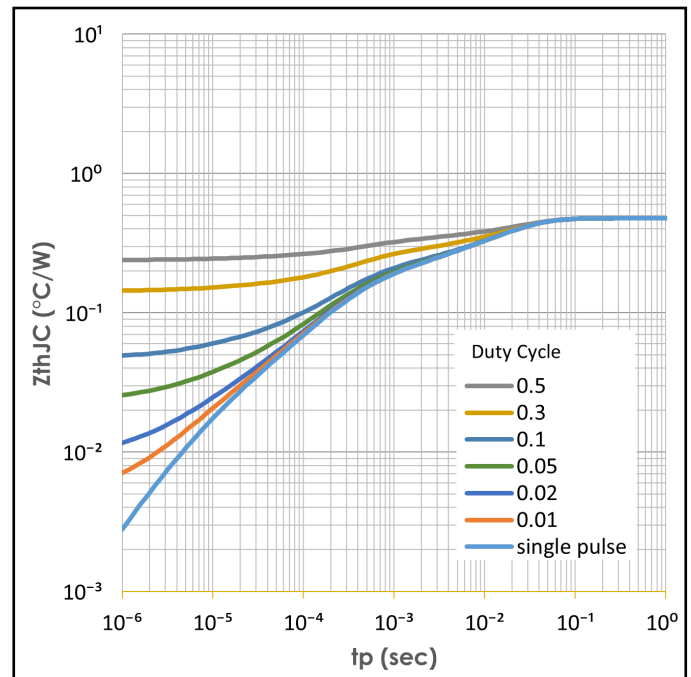


Figure 6: Max Transient Thermal Impedance

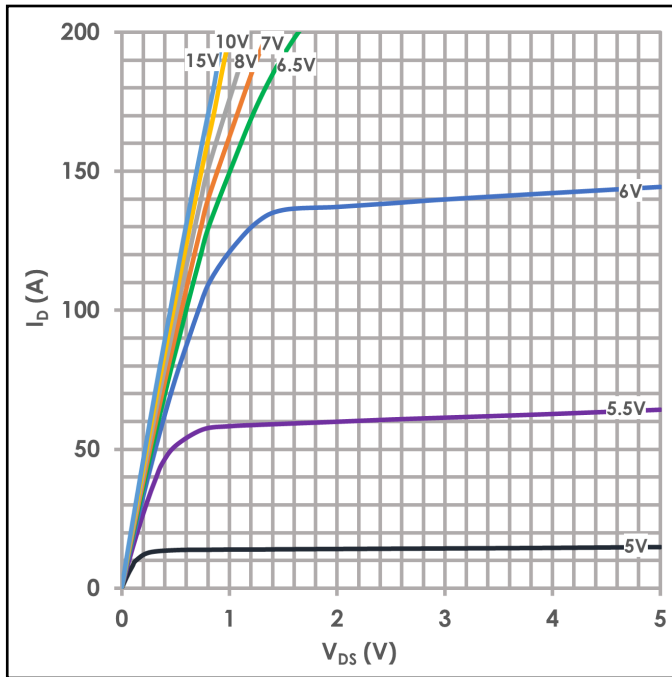


Figure 7: Typical Output Characteristics

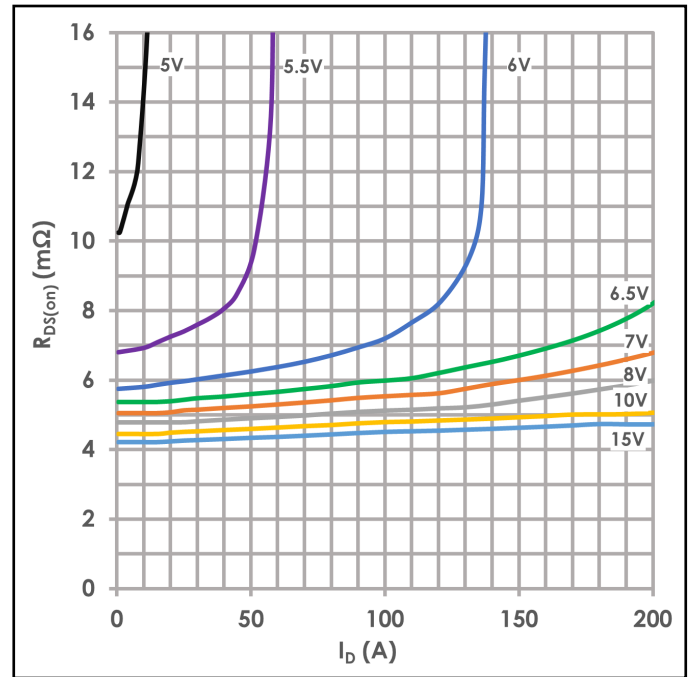


Figure 8: Typical Drain-Source On-Resistance

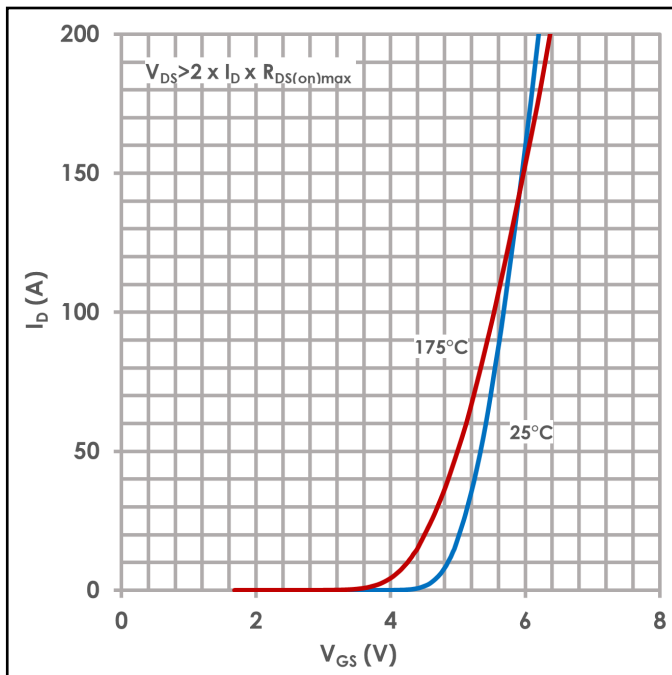


Figure 9: Typical Transfer Characteristics

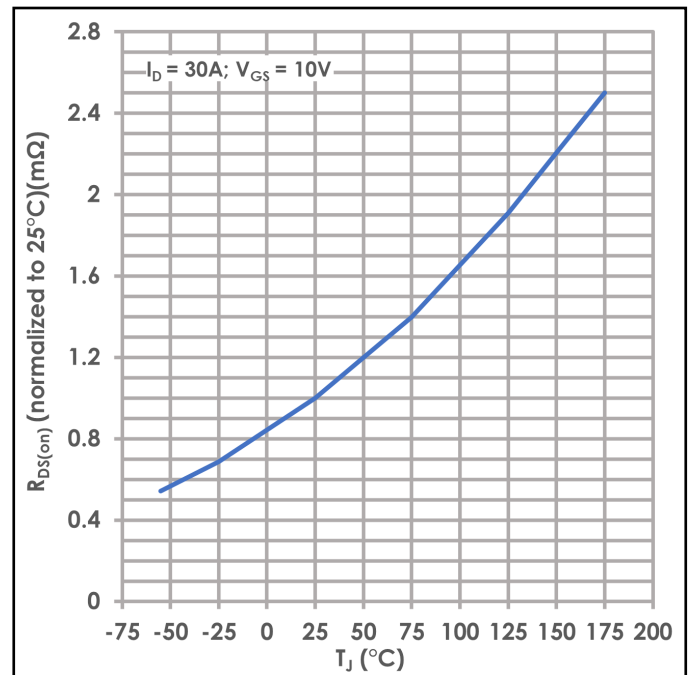


Figure 10: Normalized On-State Resistance vs. Temperature

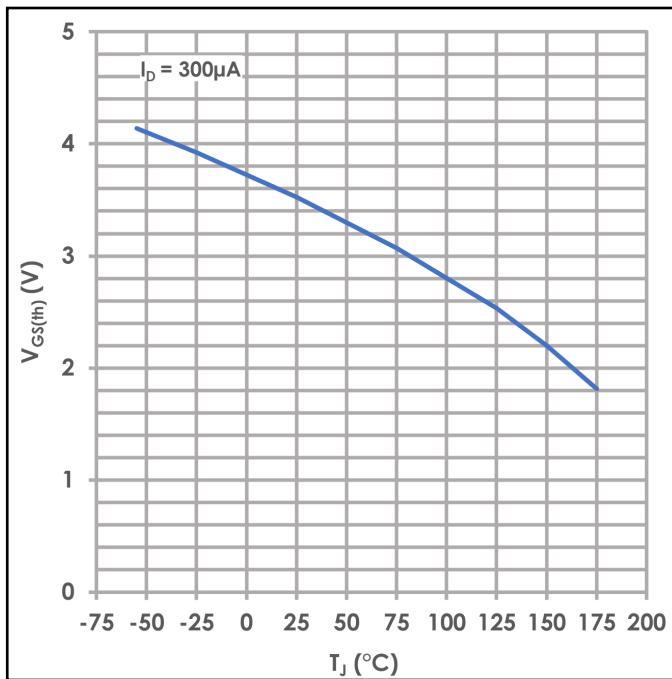


Figure 11: Typical Threshold Voltage

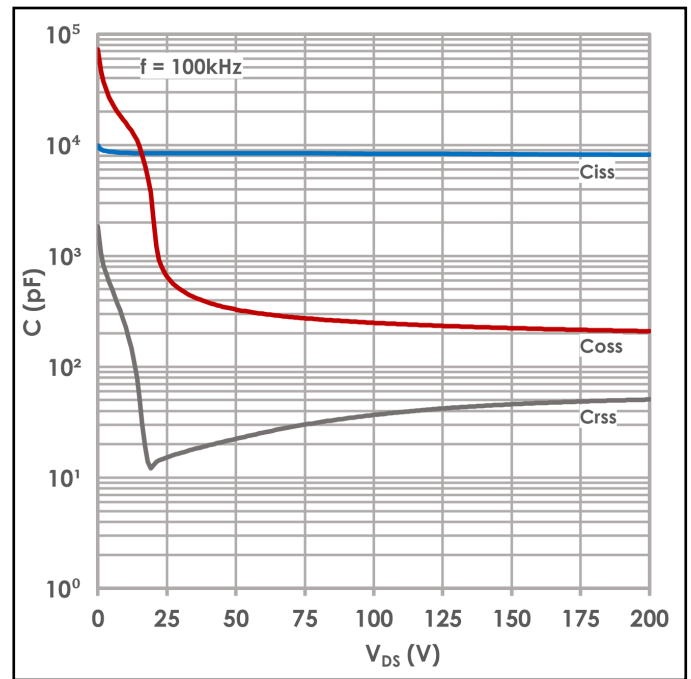


Figure 12: Typical Capacitances

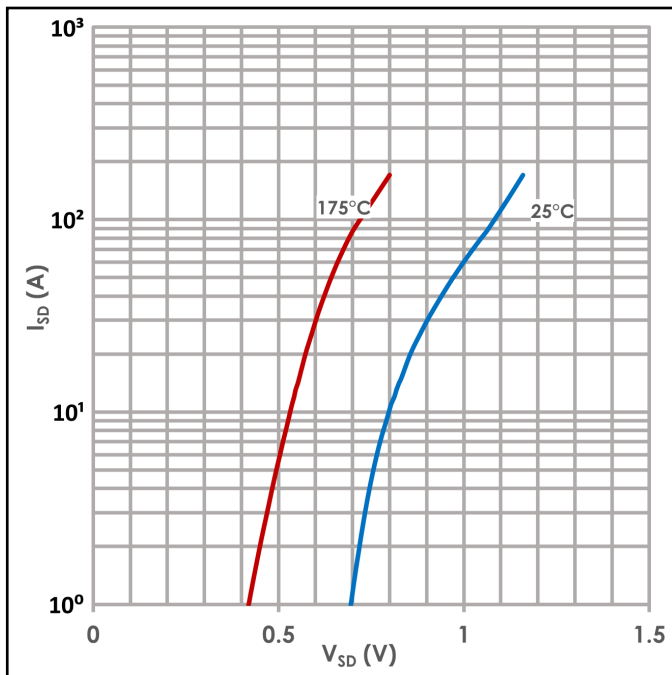


Figure 13: Typical Diode Forward Voltage

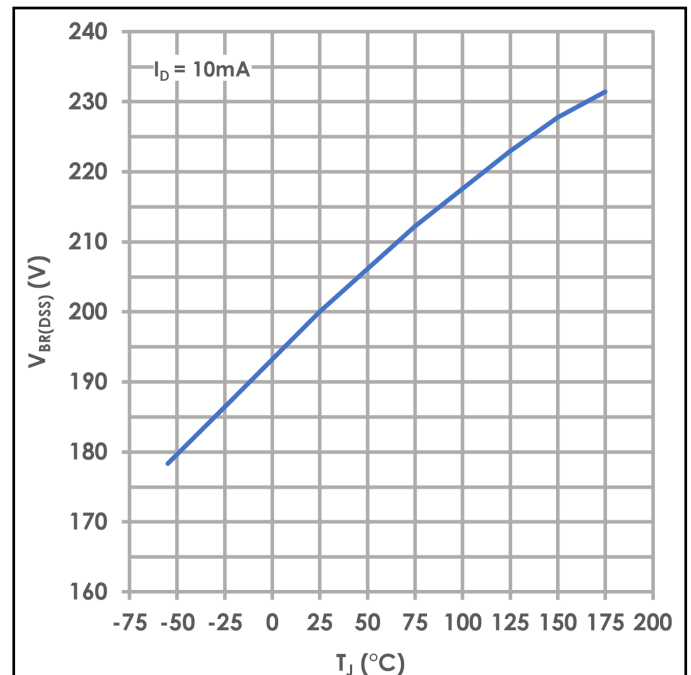


Figure 14: Min Drain-Source Breakdown Voltage

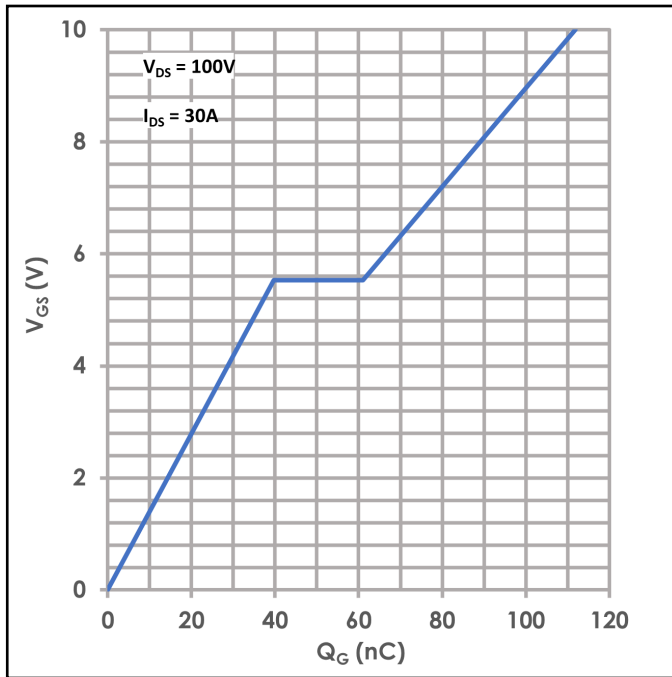


Figure 15: Typical Gate Charge

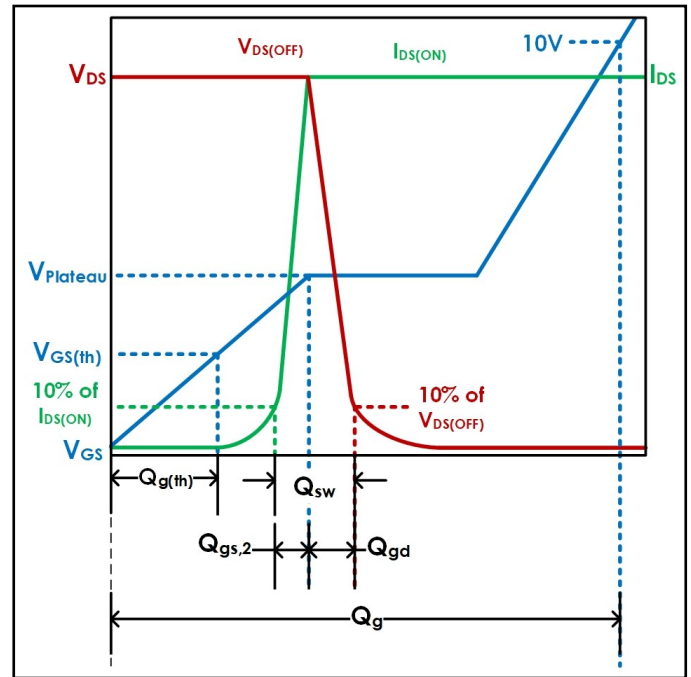
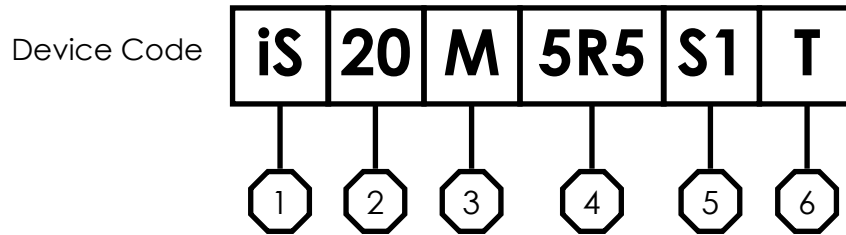








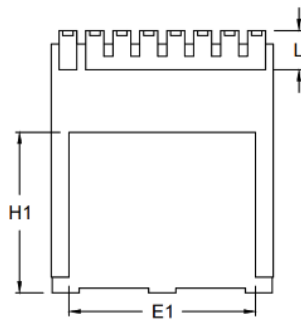
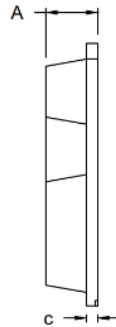
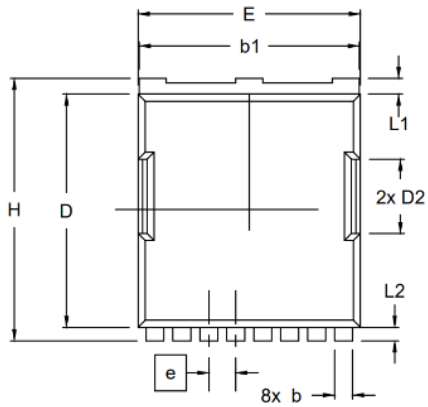
Figure 16: Gate Charge Definitions

DEVICE DECODER RING



-  — iDEAL Semiconductor product
-  — Voltage rating divided by 10 (200V)
-  — M = N-Channel MOSFET, Standard Threshold
-  — Maximum drain-to-source resistance
-  — SuperQ™ Generation
-  — T = TOLL

TOLL Package Drawing



SYMBOL	MIN	MAX
A	2.20	2.40
b	0.70	0.90
b1	9.70	9.90
c	0.40	0.6
D	10.28	10.58
D2	3.10	3.50
E	9.70	10.00
E1	7.90	8.60
e	1.20 BSC	
H	11.48	11.880
H1	6.75	7.43
L	1.40	2.10
L1	0.60	0.80
L2	0.500	0.700
θ	10° REF	

Notes:

1. All linear dimensions in millimeters

Revision History		
Version	Date	Comments
1.0	January 2026	Initial Release
1.1	February 2026	Modified EAS in Abs Max, GFS, Qgs2, td(on), tr, td (off), tf, Fig 12. Typ Capacitances (scale), Changed order of plots and plot numbers

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